Special Issue

Advances in Pattern Analysis for Identity Recognition and Verification

Message from the Guest Editor

Currently we are witnesses of the fourth industrial revolution. The main characteristics of this new living model is the massive interaction of humans with machines, the generation, storing and processing of big data using A.I. algorithms and Internet of Things (IoT). A significant progress is reported recently, in the field of biometrics by incorporating deep learning models, but the task of identifying someone under varying conditions is still open. This Special issue aims to summarize the recent advances in extracting and analyzing patterns that are able to identify the owner of them. Topics may include, but are not limited to:

- Face recognition/verification
- Iris recognition/verification
- Fingerprint recognition/verification
- Ear recognition/verification
- Vein recognition/verification
- Gait recognition/verification
- EEG recognition/verification
- Behavioral biometrics
- Multimodal and adaptive biometric systems
- Adversarial machine learning for biometric systems
- Feature extraction
- Storing and processing big biometric data
- New biometric systems architectures
- New benchmark datasets
- New applications

Guest Editor

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Deadline for manuscript submissions

closed (1 November 2020)



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About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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